

Mosfet/IGTB final test solution, get the highest UPH

Index Parallel FT test solution (**Dual-die Mosfet**)



Test solution request:

4 sites discrete FT IP test

DC+UIL+RG+DVDS+**100%QA**

DC test separate to each site to average the test time to get **highest UPH!**

All modules in one cabinet to support single/dual/quad Mosfet test with hardware error-proof features

Highly integrated test solution with one datalog

Site 4 QA(DC)

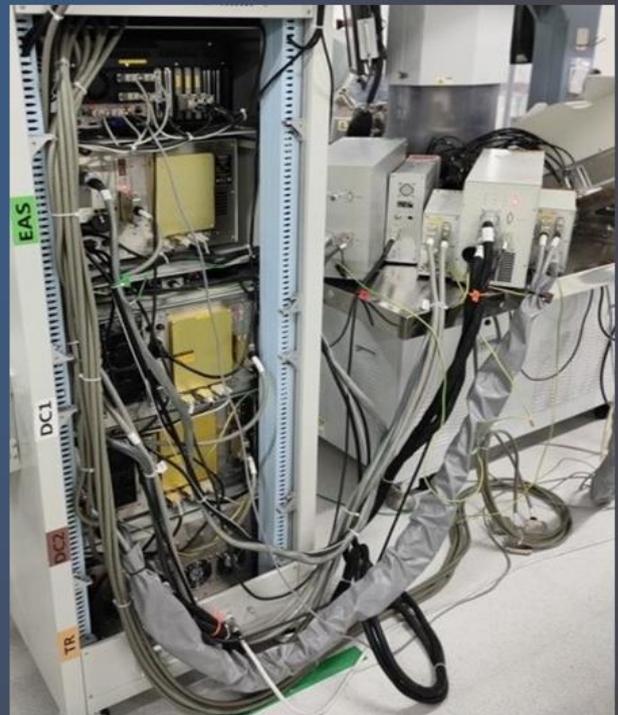
Site 3 DC

Site 2 DC+UIL

Site 1 DVDS+DC+Rg



Competitor's solution in production:

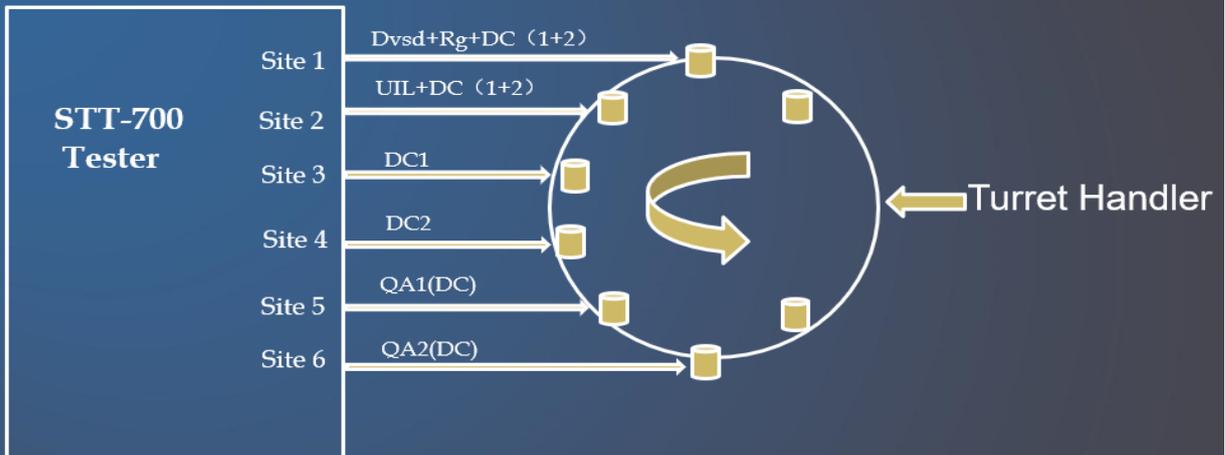


Competitor's solution is very mess and not easy setup and debug.

The final test solution of SineTest is highly integrated with higher UPH, without mess cable and also space saving, easy to set up and debug. It's the new generation discrete device final test solution.

FT Solution -- Index Parallel Six Sites Test

(high UPH for dual-mosfet test)



Index-Parallel test is the best final test solution for discrete device:

- Each station use dedicated instrument and can have different test items
- Total test time is decided by the longest test time station
- Finally will have one datalog for all sites
- Can have real on line 100% DC QA with independent DC test module

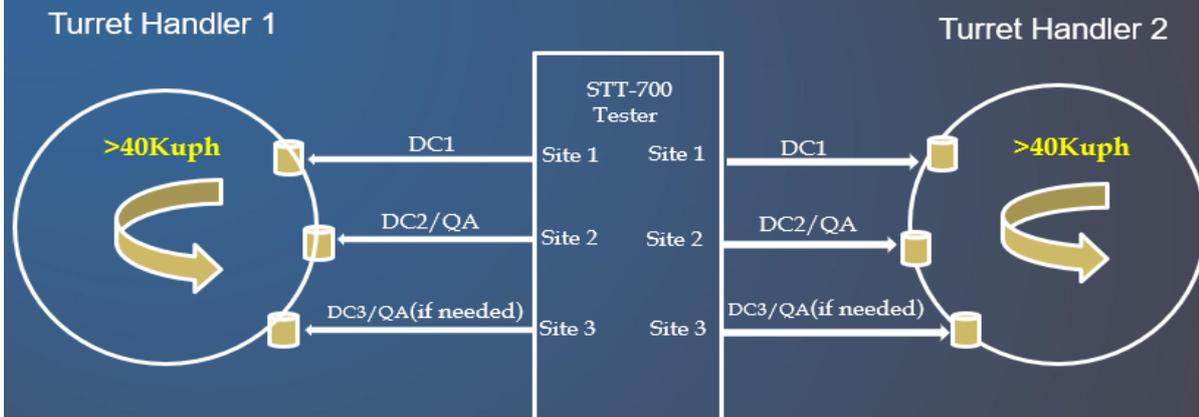
Benefits:

- Improve the UPH
- Better accuracy(100% on-line QA)

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Small signal device (diode/TVs/BJT/Mosfet) test solution

(highest UPH solution >40K)



Index-Parallel test is the best final test solution for discrete device(with turret handler):

- Each station use dedicated instrument and can have different test items
- Total test time is decided by the longest test time station
- Finally will have one datalog for all sites
- Can have real on line 100% DC QA with independent DC test module

Benefits:

- Improve the UPH
- Better accuracy(100% on-line QA)